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Campaign to identify the future CMS sensor baseline

Tuesday 1 June 2010 14:30 (20 minutes)

CMS ordered a large variety of wafers in different thicknesses and technologies at HPK.

Thicknesses from 50 - 300um are explored on floatzone, magnetic Czochralski and EPI material. Wafers are all coming in p-in-n and n-in-p versions.

 $\label{thm:contains} Every \ wafer \ contains \ different \ structures \ to \ answer \ different \ questions, e.g. \ geometry, Lorentz \ angle, \ radiation \ tolerance, \ annealing \ behaviour.$

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